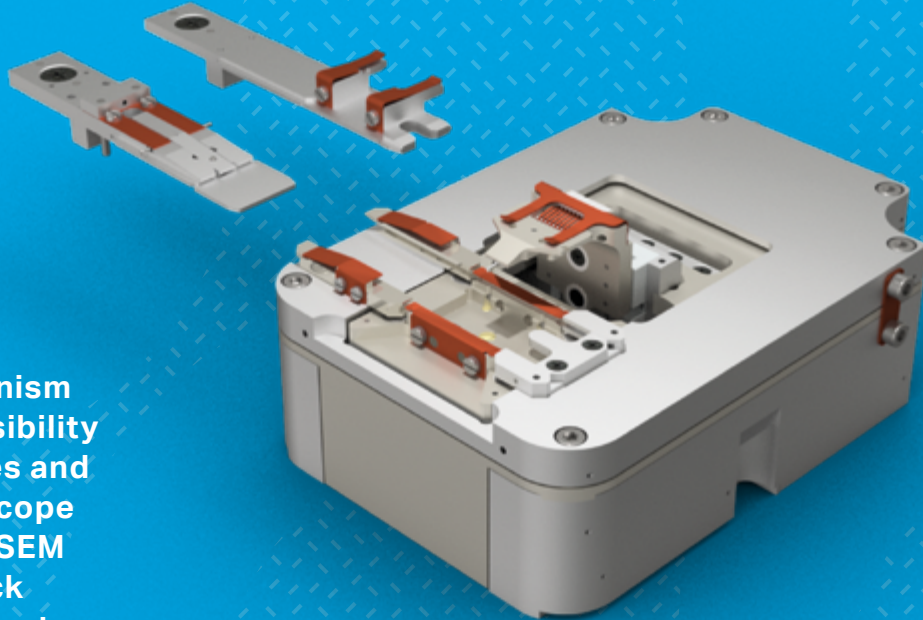




NenoVision

Load-lock mechanism Accessory for AFM-in-SEM LiteScope™



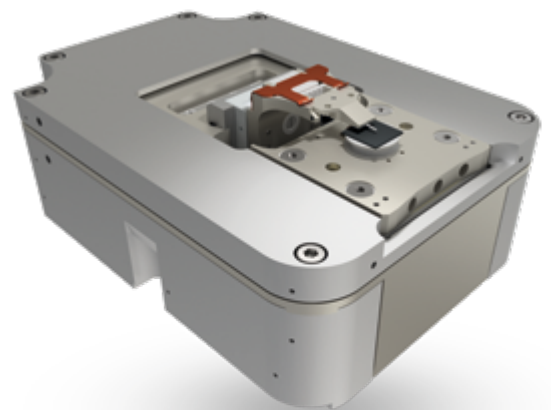
Load-lock mechanism provides the possibility of loading samples and probes into LiteScope using a standard SEM Air-lock/Load-lock sample transfer system.

LiteScope™

Atomic Force Microscope LiteScope

LiteScope is an atomic force microscope (AFM) specially designed for integration into SEM systems. It is equipped with unique Correlative Probe and Electron Microscopy (CPEM) technology allowing simultaneous measurement of both SEM and AFM images and precise in-time image correlation resulting in a 3D CPEM view.

Load-lock mechanism improves measurement workflow and user experience with LiteScope.



Key load-lock advantages

- Time-saving solution for sample/probe exchange
- No need to open and vent SEM chamber for sample or probe exchange
- Simple operation via NenoView SW
- Spectroscopy modes
- Usable with standard manual SEM Air-lock/Load-lock systems
- Easier loading/unloading of
 - Samples
 - Variety of AFM probes



Simple exchange procedure

LiteScope load-lock mechanism consists of two adaptation arms that are directly connected to SEM Air-lock/Load-lock transfer arm. With sample loading, the adaptor allows the user to load samples directly into the LiteScope head by manual SEM transfer arm. With probe loading adaptor, the user (just) loads the probe onto the head of the LiteScope, which will grab the probe automatically.

Specification

- Sample size up to 15 mm × 12 mm × 9,5 mm
- Sample weight up to 20 g
- Compatible with all standard LiteScope probes
- New design of specific probe holders
- Suitable for JEOL, TESCAN, and ZEISS systems

Additional features

It is still possible to manipulate the LiteScope on air even when the load-lock mechanism is installed on it. In this way, the user can also use the standard LiteScope sample holders.

